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Efficient delayed fluorescence *via* triplet-triplet annihilation for deep-blue electroluminescence<sup>†</sup>

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Four 2-(styryl)triphenylene derivatives (TSs) were synthesized for deepblue dopant materials. By using a pyrene-containing compound, DMPPP, as the host, the TS-doped devices exhibited significant delayed fluorescence *via* triplet-triplet annihilation, providing the highest quantum efficiency of 10.2% and a current efficiency of 12.3 cd  $A^{-1}$ .

Recently, it has been reported that the performance limitation of fluorescent OLEDs can be overcome by the up-conversion of triplet to singlet states *via* two possible mechanisms, namely, thermally activated delayed fluorescence (TADF)<sup>1</sup> and triplet–triplet annihilation (TTA).<sup>2,3</sup> In the case of TADF, the small singlet–triplet energy gap ( $\Delta E_{ST}$ ) of the material enables triplet excitons to undergo reverse intersystem crossing to form singlet excitons. Although TADF materials can provide very high device efficiency, most TADF-based OLEDs show large efficiency roll-off and low device luminance.<sup>1</sup> Therefore, TTA materials with high EL efficiencies are considered to be potential candidates for practical use.

In this communication, we report four new deep-blue dopants containing 2-(styryl)triphenylene (TS) as the core moiety, namely TSCz, TSTA, TSNA, and TSMA (Fig. 1). The deep-blue OLEDs fabricated using 1-(2,5-dimethyl-4-(1-pyrenyl)phenyl)pyrene (DMPPP) doped with one of the TSs as an emitting layer show delayed



Fig. 1 Molecule structures of host and dopants.

electroluminescence and exhibit very high EL efficiencies with  $\text{CIE}_y$  less than 0.14. Enhanced by delayed fluorescence (DF), the device doped with TSTA shows the highest external quantum efficiency (EQE) of 10.2%, a current efficiency of 12.3 cd  $\text{A}^{-1}$ , and a luminance of 68 670 cd  $\text{m}^{-2}$ . The EQEs and current efficiencies of these doped OLEDs increased with an increase in luminance, without compromising on the efficiency, owing to the increased TTA contribution at larger applied voltages.<sup>3,4</sup>

DMPPP, a pyrene-containing compound (Fig. 1), has been used as a host material for fluorescent blue devices.<sup>5</sup> With a solid quantum efficiency ( $\Phi_{PL}$ ) of 0.85 and a singlet energy gap of 3.2 eV, DMPPP is considered to be a suitable host for TS-doped devices. The  $\Phi_{\rm PL}s$  of TSs in cyclohexane are near 0.90. However, the  $\Phi_{\rm PL}s$  of DMPPP films doped with 2% TSTA, TSNA, or TSMA were as high as 0.99 except for that of the film doped with TSCz. In addition, a complete energy transfer of DMPPP excitons to TSTA leading to only TSTA emission was observed for the 2% TSTA-DMPPP film (Fig. S3, ESI<sup>†</sup>). The high PL efficiencies of TSs in cyclohexane, the efficient energy transfer from DMPPP to TSs and the restricted rotation of the aromatic rings in the dopant and host molecules in the film that reduces the fluorescence quenching caused by rotation likely account for the very high  $\Phi_{\rm PL}s$  of the TS-doped thin films.<sup>6</sup> The UV absorption spectra of TSs in toluene and the photoluminescence (PL) spectrum of DMPPP are shown in Fig. S1 (ESI<sup>+</sup>). The maximum absorptions of TSs appear in the range of 350-400 nm, characteristic of  $\pi$ - $\pi$ \* transitions. Compared with TSCz, TSMA, TSTA, and TSNA show better overlap of the absorption spectra with the PL spectrum of DMPPP. These results plausibly account for the observed lower  $\Phi_{\rm PL}$  of the TSCz-doped DMPPP film. Further photophysical and thermal properties of TSs (see Fig. S1-S4, ESI<sup>+</sup>) are summarized in Table 1. Due to the high photoluminescence quantum efficiencies of DMPPP and TSs which lead to little or no intersystem crossing from singlet to triplet excited states, we were unable to measure their phosphorescent PL spectra at 77 K. Similarly, we measured the transient PL of the DMPPP film and of TSs in degassed toluene and no DF was observed for these compounds. These results exclude the possibility that DMPPP and TSs are TADF materials, in view of the fact that TADF materials in general show delayed fluorescence in

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Table 1 Photophysical and thermal properties of TSs

Compd	$Abs_{sol}^{a}(nm)$	$\mathrm{PL}_{\mathrm{sol}}^{a}\left(\mathrm{nm}\right)$	$\mathrm{PL_{film}}^{b}(\mathrm{nm})$	HOMO <sup><math>c</math></sup> , LUMO <sup><math>d</math></sup> (eV)	$E_{\rm g}^{\ e}$ (eV)	$T_{g}^{f}, T_{d}^{g}(^{\circ}\mathrm{C})$	${\Phi_{ ext{PL}}}^h$
TSCz TSTA TSNA	358 308, 386 386	420, 442 441, 462 441, 462	469 470 469	5.37, 2.57 5.38, 2.65 5.38, 2.65	2.80 2.73 2.73	112, 431 108, 431 119, 448	0.85 (0.92) 0.89 (>0.99) 0.90 (>0.99)
TSMA	308, 392	451	476	5.23, 2.53	2.70	100, 421	0.90(0.99)

<sup>*a*</sup> Absorption and PL spectra measured in toluene with concentration =  $1 \times 10^{-5}$  M. <sup>*b*</sup> PL spectra measured in the thin film. <sup>*c*</sup> Determined by using a photoelectron spectrometer (AC-II). <sup>*d*</sup> LUMO = HOMO –  $E_g$ . <sup>*e*</sup> Band gaps were estimated from the optical absorption threshold in the films. <sup>*f*</sup> Glass-transition temperature determined by DSC with a heating rate of 20 °C min<sup>-1</sup> under N<sub>2</sub>. <sup>*g*</sup> Onset decomposition temperature, as measured with 5% mass loss by TGA with a heating rate of 20 °C min<sup>-1</sup> under N<sub>2</sub>. <sup>*h*</sup> Fluorescence quantum efficiency, relative to 9,10-diphenylanthracene in cyclohexane ( $\Phi_{PL} = 0.90$ ); the data presented in the parentheses are the solid state photoluminescence quantum efficiency of the dopants in the DMPPP thin film measured by an integral sphere with the excitation wavelength of 310 nm.

the transient PL because the small  $\Delta E_{ST}$  leads to the possibility of  $T_1 \rightarrow S_1$  to produce DF.<sup>1</sup> The calculated HOMO and LUMO density maps of the TS series (Fig. S5, ESI<sup>†</sup>) also do not support that they are TADF materials.<sup>1</sup>

Subsequently, we fabricated OLEDs using the emission layer containing DMPPP doped with one of the TS compounds, designated as A, B, C, and D, respectively. The device structure consists of ITO/NPNPB: 10% MoO<sub>3</sub> (5 nm)/NPNPB (80 nm)/NPB (10 nm)/DMPPP: 5% dopant (25 nm)/BAlq<sub>2</sub> (20 nm)/LiF (1 nm)/ Al (100 nm). A thin layer of NPNPB (N,N'-di-phenyl-N,N'-di-[4-(N,N-di-phenyl-amino)phenyl]benzidine) doped with 10% MoO<sub>3</sub> was used as the hole injection layer, in order to reduce the hole injection barrier.<sup>7</sup> All the devices fabricated in this study showed deep-blue EL emissions, with maximum peaks at around 450 nm and CIE<sub>y</sub>  $\leq$  0.14 (Fig. S6, ESI†). Fig. 2 shows the dependence of the EQE and the current efficiency of the devices on luminance.



Fig. 2 EQEs and current efficiencies vs. luminance for devices A-E.

 Table 2
 Electroluminescence performance of devices A-F

For device A, the EQE and current efficiency *vs.* luminance was nearly flat. On the other hand, the EQEs and current efficiencies of devices B, C, and D gradually increased with an increase in luminance from 10 to 30 000 cd m<sup>-2</sup>. These results are rather intriguing, as most OLED devices show obvious efficiency roll-off. Furthermore, devices B, C, and D exhibited very high EQEs of 10.2, 8.5 and 8.9%, respectively, and excellent current efficiencies of 12.3, 8.9 and 10.3 cd A<sup>-1</sup>, respectively. It should be noted that the EQEs of all four OLEDs fabricated in this study are much higher than the conventional upper limit of 5%. Furthermore, the operating lifetime of all the four OLEDs was tested under an initial luminance of 2000 cd m<sup>-2</sup> (Fig. S8, ESI†). Device C showed the longest operation lifetime of about 210 h, which is projected to be about 680 h at 1000 cd m<sup>-2</sup> according to the empirical lifetime acceleration function,  $L_0^{1.7} \times t_{50} = \text{const.}^8$ 

To gain further insights into the observed unusually high efficiency of the doped blue devices, we also fabricated non-doped devices E and F with the same configuration as that of devices A-D, except that only DMPPP and TSTA were used, respectively, in the emitting layer. Both devices E and F exhibited relatively low device efficiency compared with that of the doped devices (Table 2). It is likely that the high concentration of these molecules in the emitting layer leads to concentration-quenching and lowers the efficiency of these non-doped devices.9 Subsequently, we measured the transient EL of devices A-F at 450 nm (Fig. 3a). As the decay lifetime of singlet excitons is generally within several ns, the results clearly show microsecond-scale DF for all devices including the non-doped devices E and F. These surprising results indicate that both DMPPP and dopants (TSs) are able to produce DF. We also measured the transient EL of the DMPPP-based devices doped with different concentrations of TSTA in the emitting layer, namely, 2, 5, 10, 15 and 100% (Fig. 3b). The results reveal that the dopant used and

	tectoluminescence performance of devices A-F											
Device	$\mathrm{EML}^{a}$	$V_{\rm on}{}^b$	$EQE^{c}$	$\eta_{c}^{d}$	$\eta_{ m p}^{\ e}$	$L_{\max}^{f}$	$\lambda_{\max}^{g}$	CIE $(x, y)^h$	$t_{50}{}^{i}$			
A	5% TSCz	4.4	6.7 (10.6 V)	7.1 (10.6 V)	3.8 (5.2 V)	33 510 (18.6 V)	448	0.15, 0.10	75			
В	5% TSTA	3.8	10.2 (15.0 V)	12.3 (15.0 V)	5.7 (3.8 V)	68 670 (18.2 V)	454	0.14, 0.14	100			
С	5% TSNA	3.6	8.5 (14.2 V)	8.9 (14.2 V)	4.8 (4.6 V)	49 060 (17.2 V)	450	0.14, 0.11	210			
D	5% TSMA	3.4	8.9 (15.0 V)	10.3 (15.0 V)	8.7 (3.4 V)	58 640 (18.0 V)	460	0.14, 0.14	35			
E	DMPPP	4.8	3.5 (8.2 V)	3.2 (9.6 V)	1.3 (7.2 V)	10 840 (18.0 V)	444	0.16, 0.10	_			
F	TSTA	3.6	4.2 (7.0 V)	7.6 (7.0 V)	3.8 (5.0 V)	30 584 (20.0 V)	470	0.14, 0.25	_			

<sup>*a*</sup> Emission layer of devices A–F: DMPPP/5% dopant. <sup>*b*</sup> The voltage at 10 cd m<sup>-2</sup> (V). <sup>*c*</sup> Maximum external quantum efficiency (%). <sup>*d*</sup> Maximum current efficiency (cd A<sup>-1</sup>). <sup>*e*</sup> Maximum power efficiency (lm W<sup>-1</sup>). <sup>*f*</sup> Maximum luminance (cd m<sup>-2</sup>). <sup>*g*</sup> The electroluminescence wavelength (nm). <sup>*h*</sup> Recorded at 8 V. <sup>*i*</sup> Operation lifetime at an initial luminance of 2000 cd m<sup>-2</sup> under constant current.



**Fig. 3** (a) Transient EL of devices A–F measured at 450 nm; (b) transient EL of the devices doped with different concentrations of TSTA (the device structure is similar to that of device B except for the concentration of TSTA) measured at 450 nm.

its concentration influence the relative DF intensity significantly. As shown in Fig. 3b, the relative DF intensity of the TSTA-doped devices decreases with increasing TSTA concentrations suggesting that a low TSTA concentration in the DMPPP host gives a relatively high DF intensity. Device B with an optimized TSTA/DMPPP ratio of 95/5 in the emitting layer contains a substantial DF contribution of the EL intensity. To further understand the DF properties of these EL devices, we tried to fit the transient EL curves in Fig. 3. A plot of the inverse of relative transient EL intensity *vs.* time (between 5 and 15  $\mu$ s) is linear for each transient EL curve (see Fig. S12 and S13 (ESI<sup>+</sup>) for the slopes). The results show that the transient EL decay is second-order to the EL intensity and supports that the DF of these devices is due to a TTA process (T<sup>1</sup> + T<sup>1</sup>  $\rightarrow$  S<sup>1</sup> + S<sup>0</sup>) which is known to be second-order with respect to the T<sup>1</sup> concentration.<sup>4,10</sup>

The delayed EL spectrum of TSTA-doped device B is slightly red shifted compared with its device and prompt EL spectra (Fig. S9, ESI<sup>†</sup>). Moreover, the delayed EL spectrum of the non-doped device E exhibits a much broader emission with a shoulder at 550 nm, which may be assigned to an excimer emission of DMPPP.<sup>11</sup> As a result, the relatively delayed EL of device E (Fig. S10, ESI<sup>†</sup>) measured at 550 nm is relatively strong than at 450 nm. The results that support that the observed DF in the present devices is due to TTA are further summarized below. One is the EQE *vs.* luminance curve which shows an increase in efficiency for higher luminance (see Fig. 2).<sup>4</sup>

a second-order process proportional to the square of the tripletexciton concentration; we expected that the triplet excitons generated by the device are nearly proportional to the current density of the device. Similarly, the dependence of luminescence on current density as shown in Fig. S15 (ESI<sup>†</sup>) is a non-linear curve. The luminescence increased more than linearly with an increase in current density, a characteristic of TTA-type devices.<sup>12</sup> The other evidence to support TTA is that the decay rate of the transient EL intensity is second-order with respect to the transient EL intensity (Fig. S12 and S13, ESI<sup>†</sup>).

In summary, we have demonstrated that DMPPP/TS-based devices are highly efficient affording the highest EQE of 10.2% and a maximum current efficiency of 12.3 cd  $A^{-1}$ . Both DMPPP and TS appear to exhibit TTA-type delayed EL. This is the first time that pyrene- and triphenylene-containing materials with TTA properties were used in OLEDs. In contrast to the TADF-based OLEDs, which generally have low maximum luminance and high roll-off efficiencies, the present devices A–D provide very high luminance in the range of 33 510–68 670 cd m<sup>-2</sup> without compromising on the efficiency.

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